

AP3 Rec'd PCT/PTO 07 JUN 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: **Youichi ARAI**

Serial Number: **Not Yet Assigned**
(§371 of International Application PCT/JP05/00679)

Filed: **June 7, 2006**

For. **METHOD OF MEASURING INTRINSIC RESISTANCE OF BATTERY
AND APPARATUS OF SAME**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 7, 2006

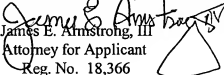
Sir:

In compliance with 37 CFR 1.56, Applicant calls to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449 and cited in the enclosed international search report. References AE-AF are cited in the international search report.

A copy of each of the references is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 01-2340.

Respectfully submitted,
ARMSTRONG, KRATZ, QUINTOS,
HANSON & BROOKS, LLP


James E. Armstrong, III
Attorney for Applicant
Reg. No. 18,366

JEA/jaz
Atty. Docket No. **060424**
Suite 1000
1725 K Street, N.W.
Washington, D.C. 20006
(202) 659-2930



23850

PATENT TRADEMARK OFFICE

Enclosures: PTO-1449; References (3); International Search Report

10/581920

AP3 Rec'd PCT/PTO 07 JUN 2008

INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. 060424	Serial No. New Application
	Applicant(s): Youichi ARAI	
	Filing Date: June 7, 2006	Group Art Unit: Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
_____	AA					
_____	AB					
_____	AC					
_____	AD					

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)	
/JZ/	AE	2003-177163	06/27/03	Japan	No
/JZ/	AF	2003-177164	06/27/03	Japan	No
/JZ/	AG	2003-115331	04/18/03	Japan	Yes-Abstract/Discussed in the specification
_____	AH				
_____	AI				

OTHER DOCUMENTS

_____	AJ	
_____	AK	
Examiner	/Jue Zhang/	Date Considered 09/01/2008